## **AMENDMENTS TO CLAIMS**

This listing of claims will replace all prior versions, and listings, of claims in the application:

## **Listing of Claims:**

- 1-3. (Canceled)
- 4. (Currently Amended) A semiconductor memory device comprising:
  - a plurality of bit lines that are adjacent to each other;
  - a plurality of gates intersecting with said bit lines;
- a plurality of active areas, each of which is connected to one of said bit lines, of which a first active area is connected with a bit line and second active area is connected with another bit line, said two bit lines being adjacent to each other, and each active area having two cells;
- a plurality of work lines, each word line being connected with one corresponding cell; a plurality of deep trenches, at least one of which communicates with only two different active areas which are respectively connected with two adjacent two of said bit lines one of the two cells located in the first active area and one of the two cells located in the second active area, so as to measure a leakage current between said two different the first and second active areas.
- 5. (Previously Presented) The device as claimed in Claim 4, wherein the cross section of said deep trench communicates with said two different active areas two different word lines respectively control two different cells in one active area.
- 6. (Canceled)